

Results of the laser-polished sample B-5.5 test (preliminary)

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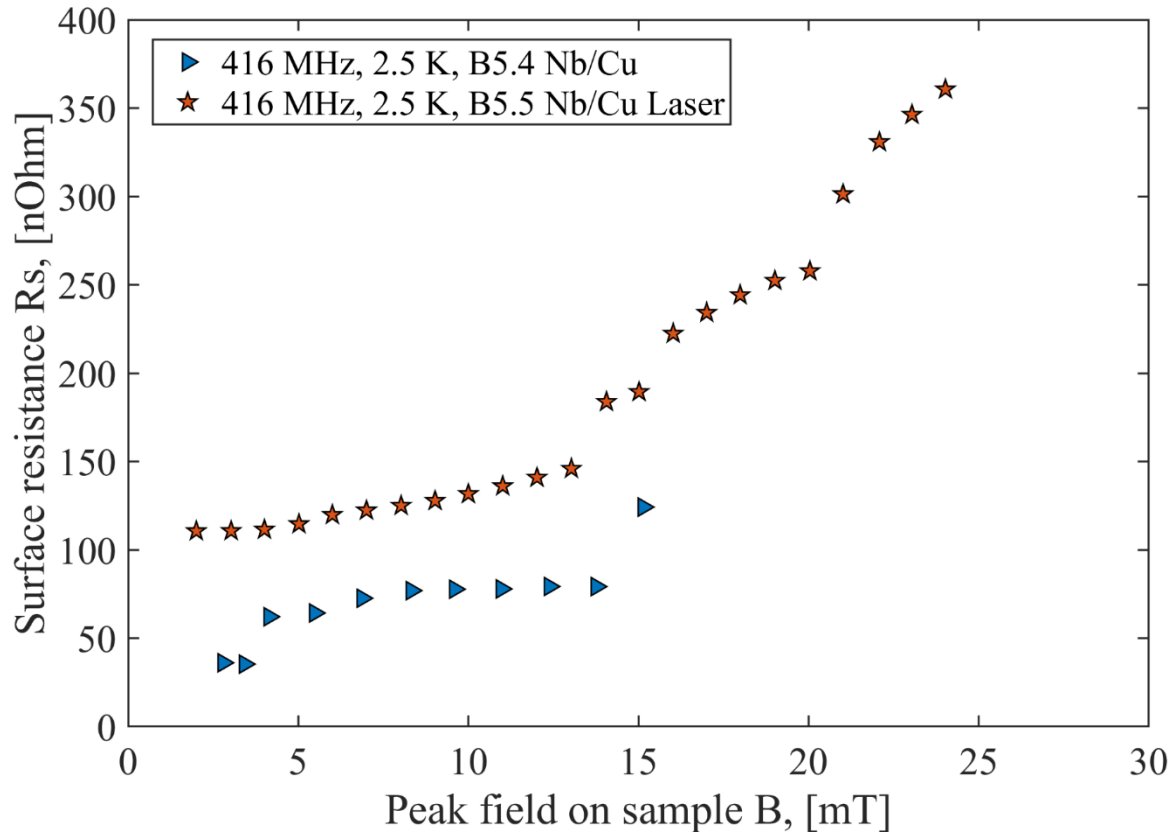
ARIES WP meeting

Presenter

Dmitry Tikhonov
Early stage researcher

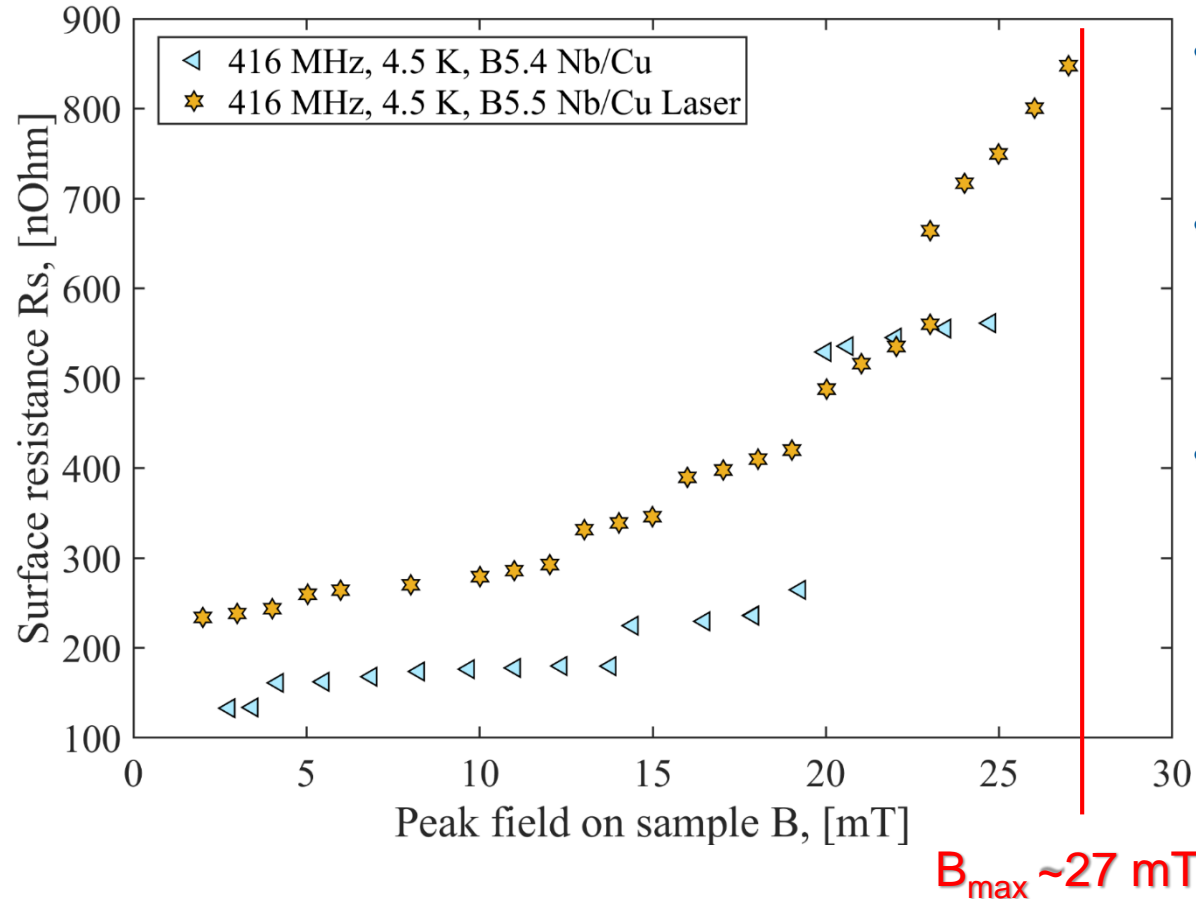
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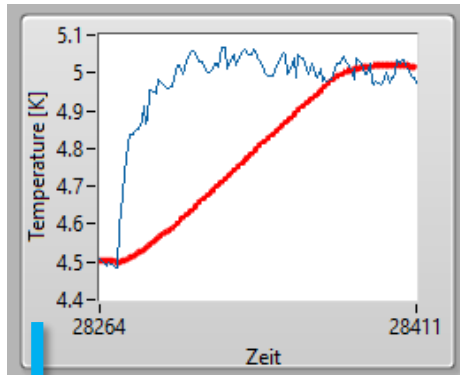
Results for pre-laser polishing and after for 2.5 K, ~400 MHz:

- Higher surface resistance

Results for pre-laser polishing and after for 4.5 K, ~400 MHz:

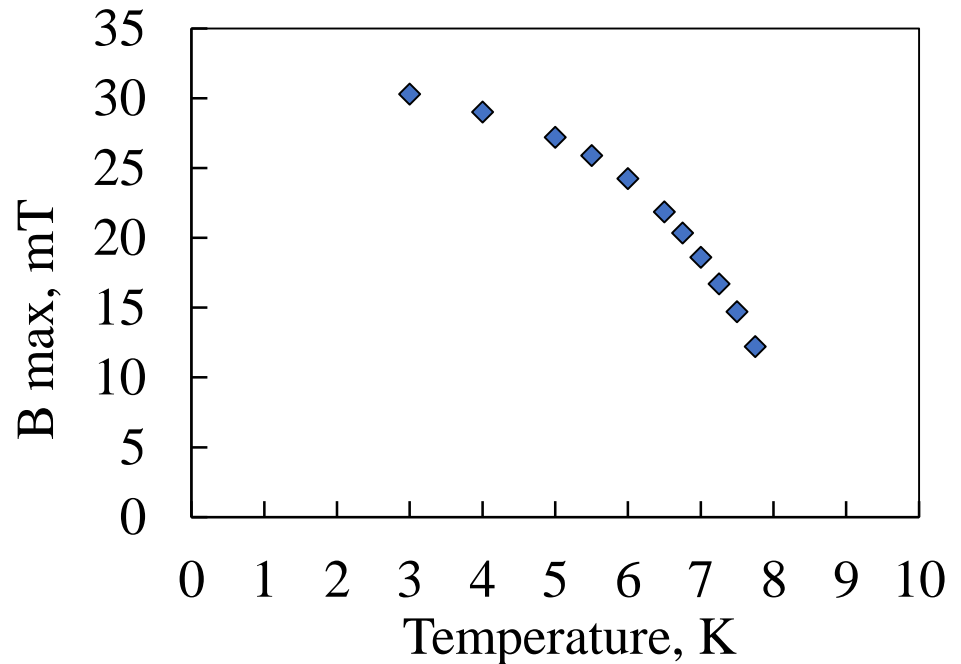
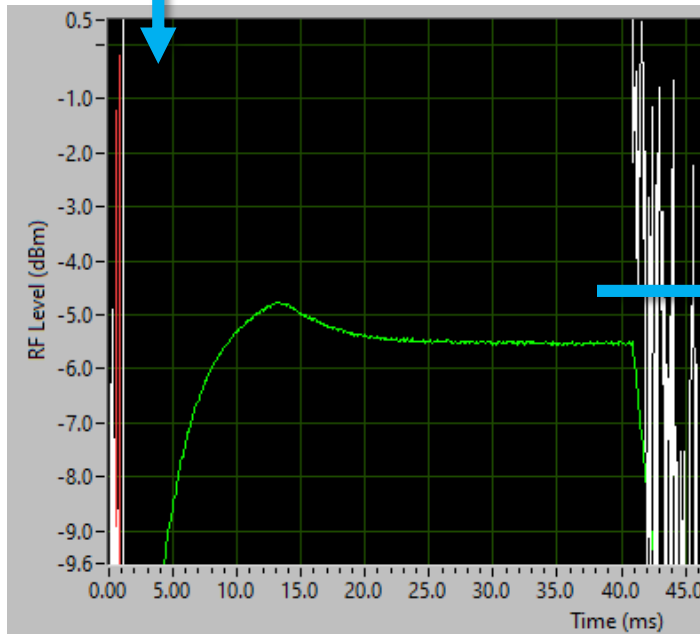


- Rs vs B is more “smooth”, one spot is better
- Possible problems: problematic spot could be at higher field region
- Maximum film is about same as previously tested (27 mT). Probably, problematic spot was not reached by laser.

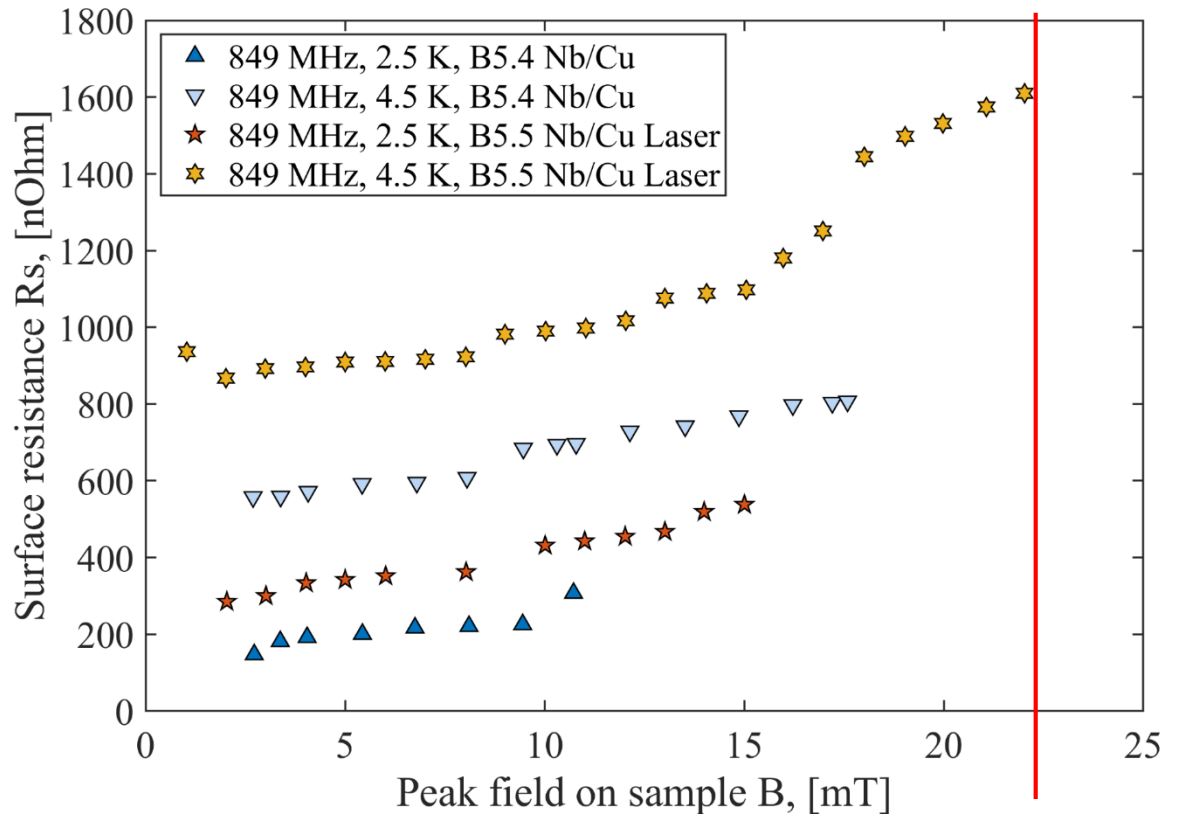


Pulse shape (transmitted)

- At max field 27 mT, 416 MHz: Temperature significantly increased (but not complete quench)
- Only part of the film quenched (not full film because temperature stays <9.3K)
- Quench field depends on temperature:

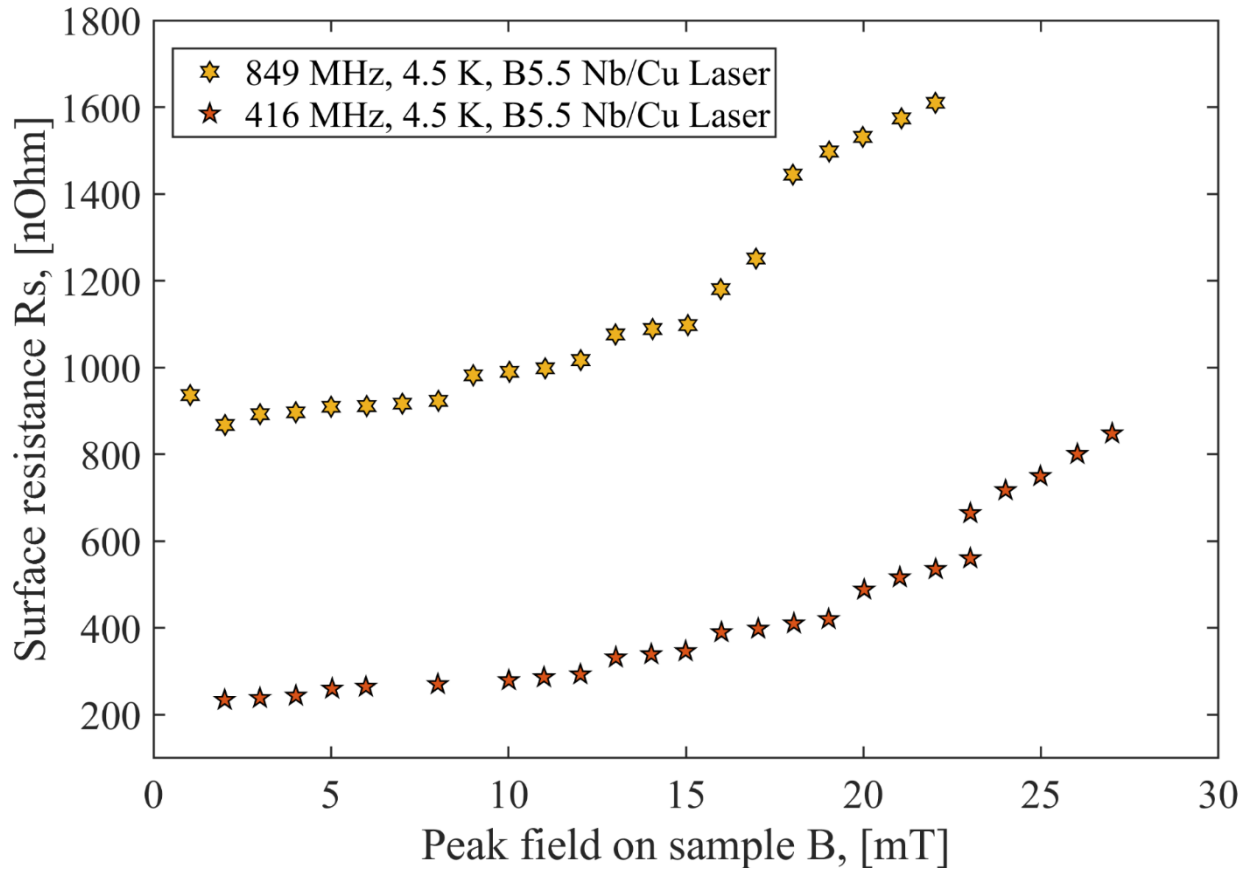


Results for pre-laser polishing and after for ~850 MHz:



- Maximum film is about 22 mT.

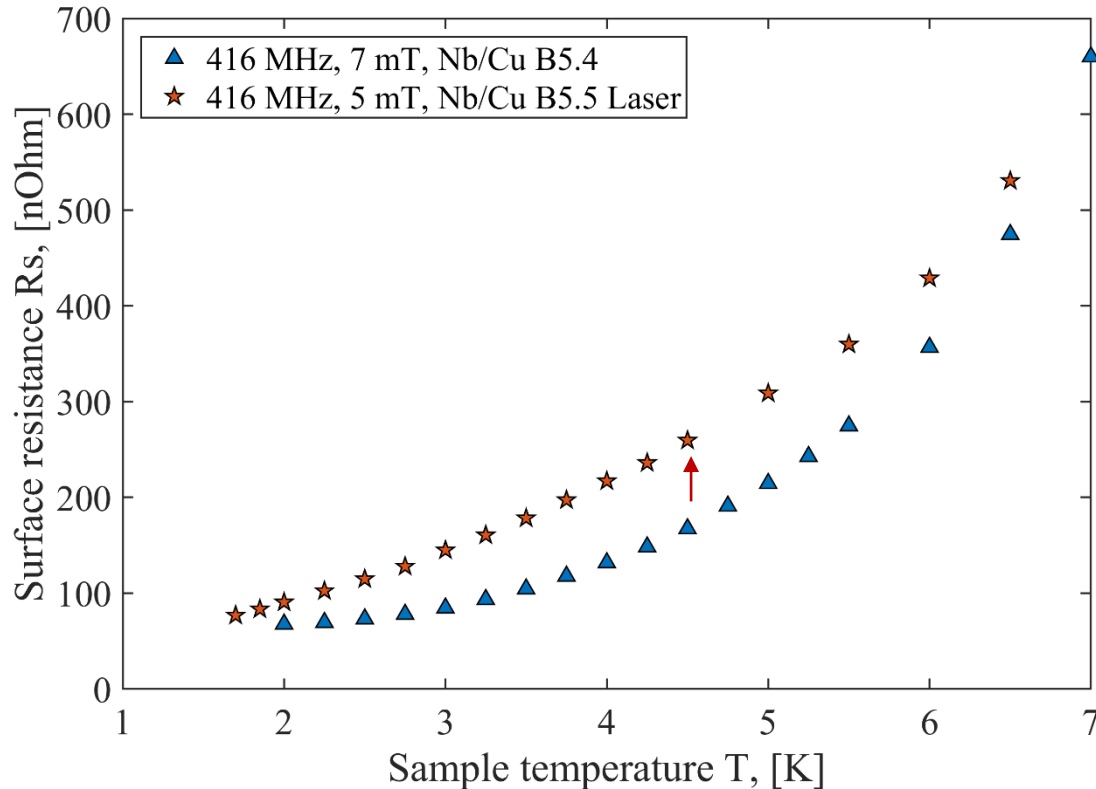
$B_{\max} \sim 22$ mT



- Q1 vs Q2



Rs vs T results for pre-laser polishing and after for ~416 MHz:



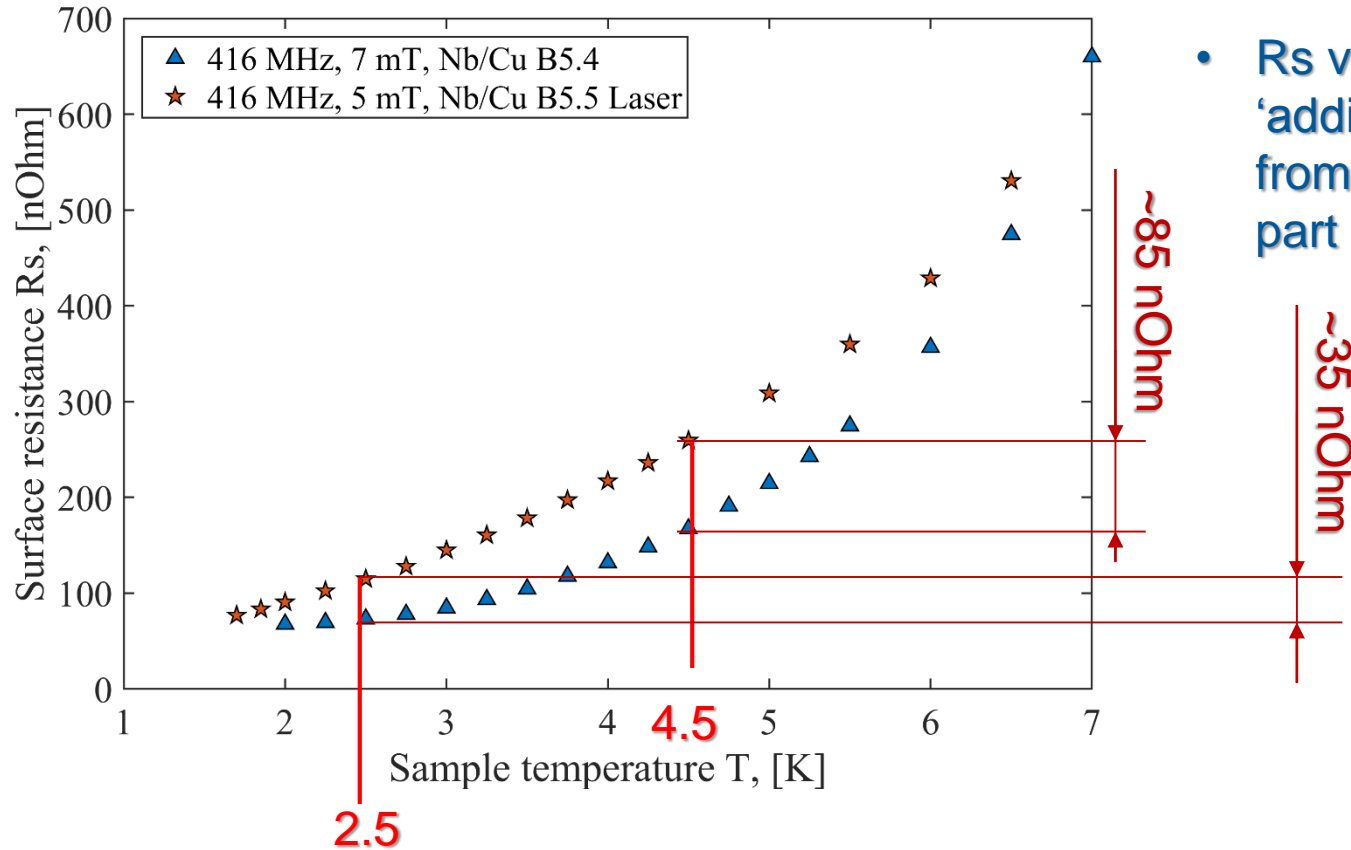
- Rs vs T: Most of the 'additional' resistance come from temperature-depend part
- Residual resistance is approximately same:

Residual resistance 'eye' estimation (416 MHz):

	R_{res}
B-5.4	~67 nOhm
B-5.5	~76 nOhm



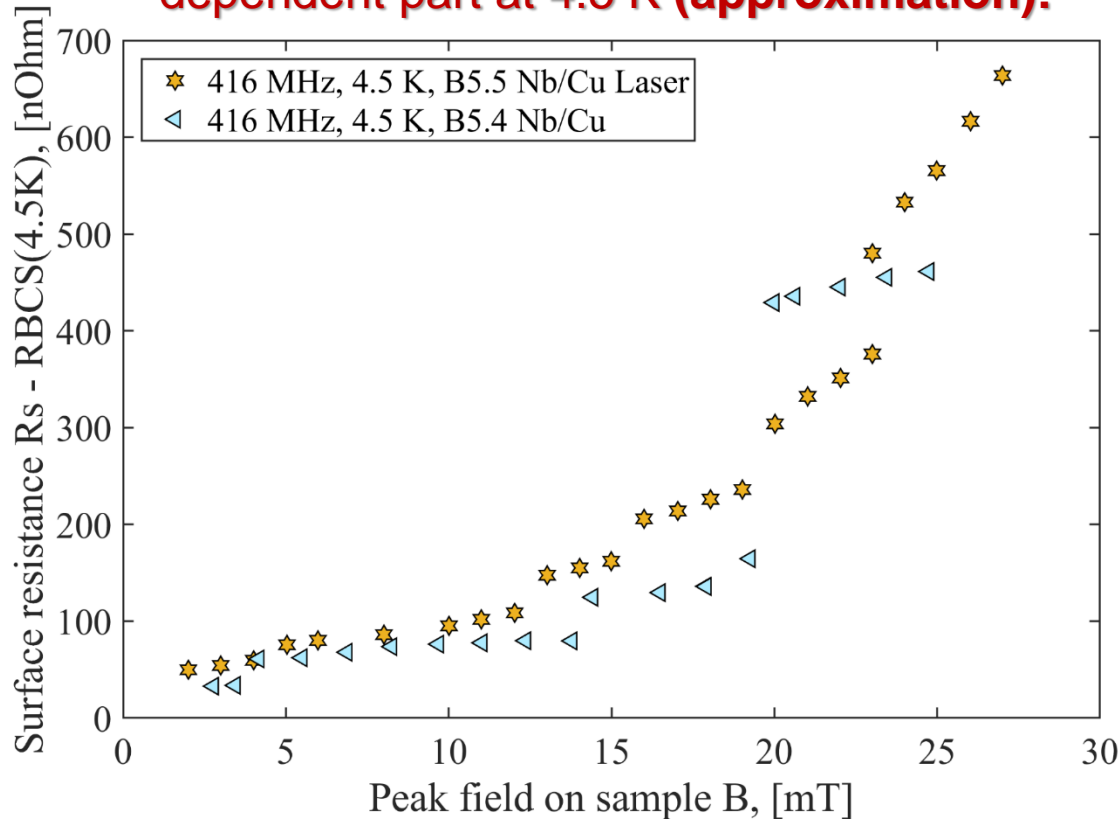
Rs vs T results for pre-laser polishing and after for ~416 MHz:



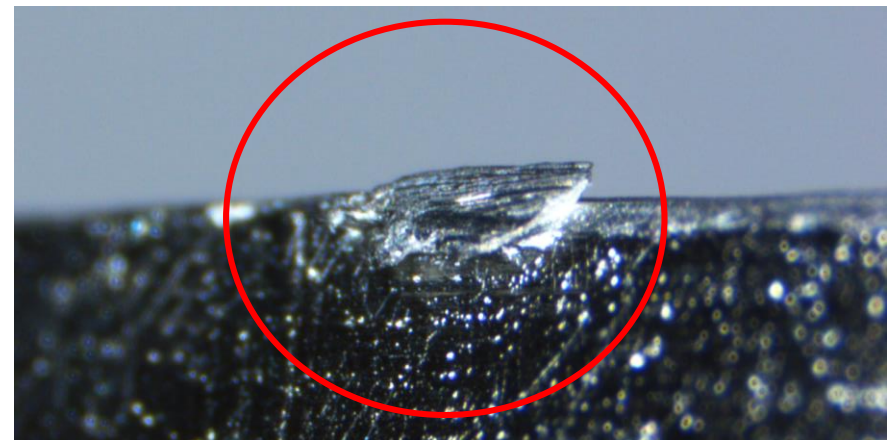
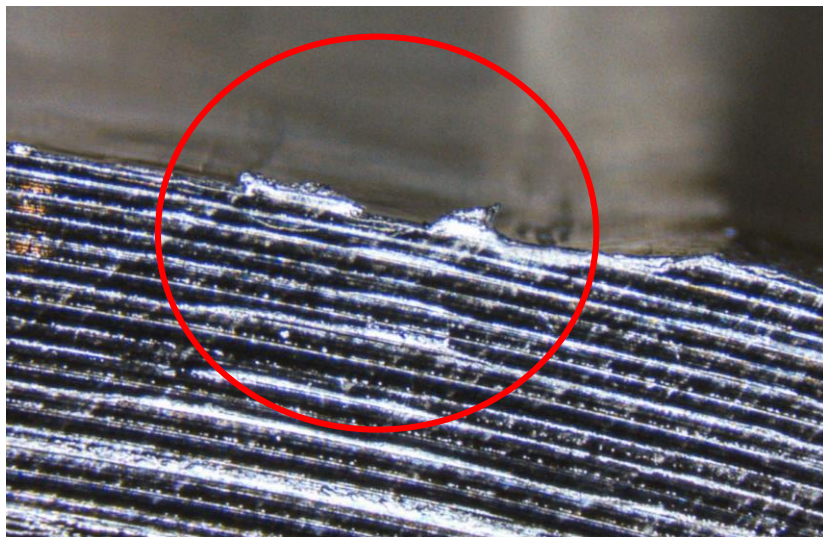
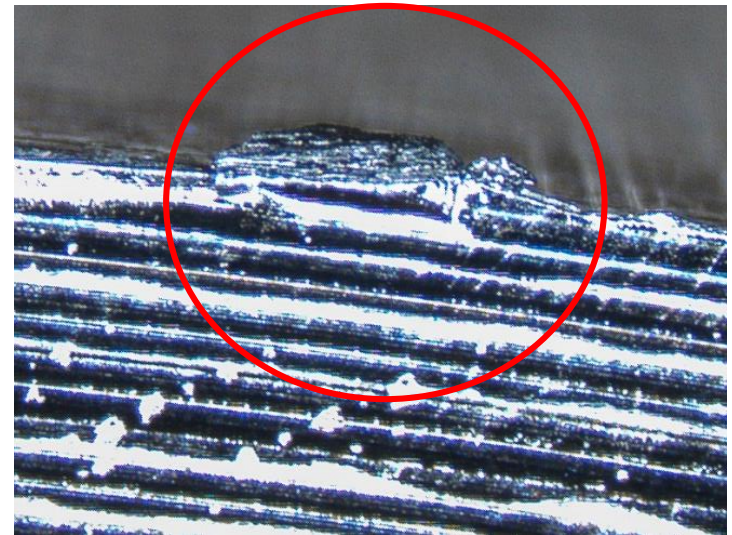
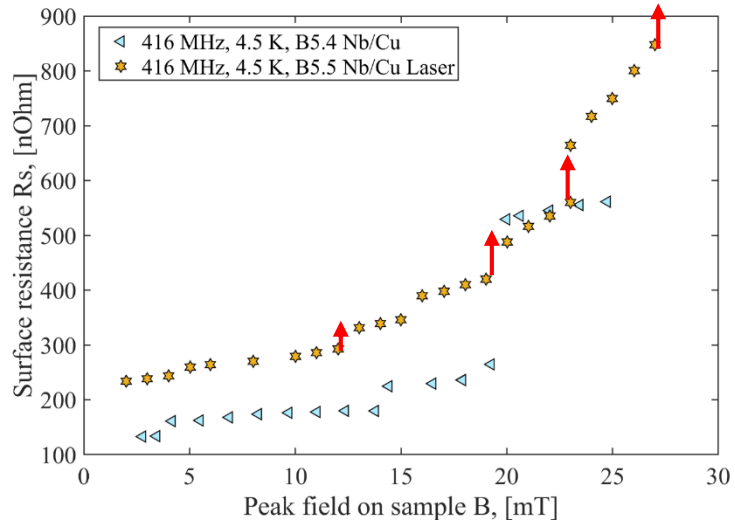
- Rs vs T: Most of the 'additional' resistance come from temperature-depend part

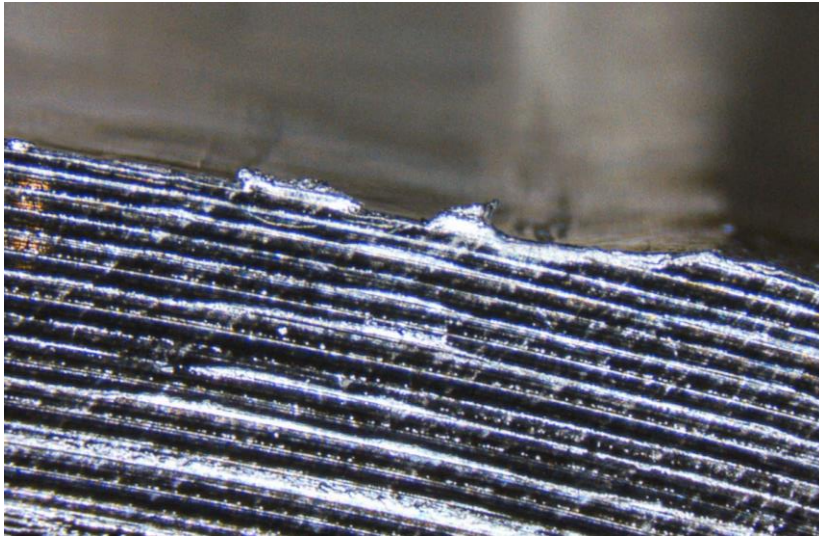
Rs vs B results for pre-laser polishing and after for ~416 MHz:

Rs with subtracted ~BCS temperature dependent part at 4.5 K (approximation):



- Probably increased BCS came from impurities and defects due to wrong polishing procedure
- With subtracted BCS contribution from both tests the field dependent part is more or less comparable except higher field 'jump'





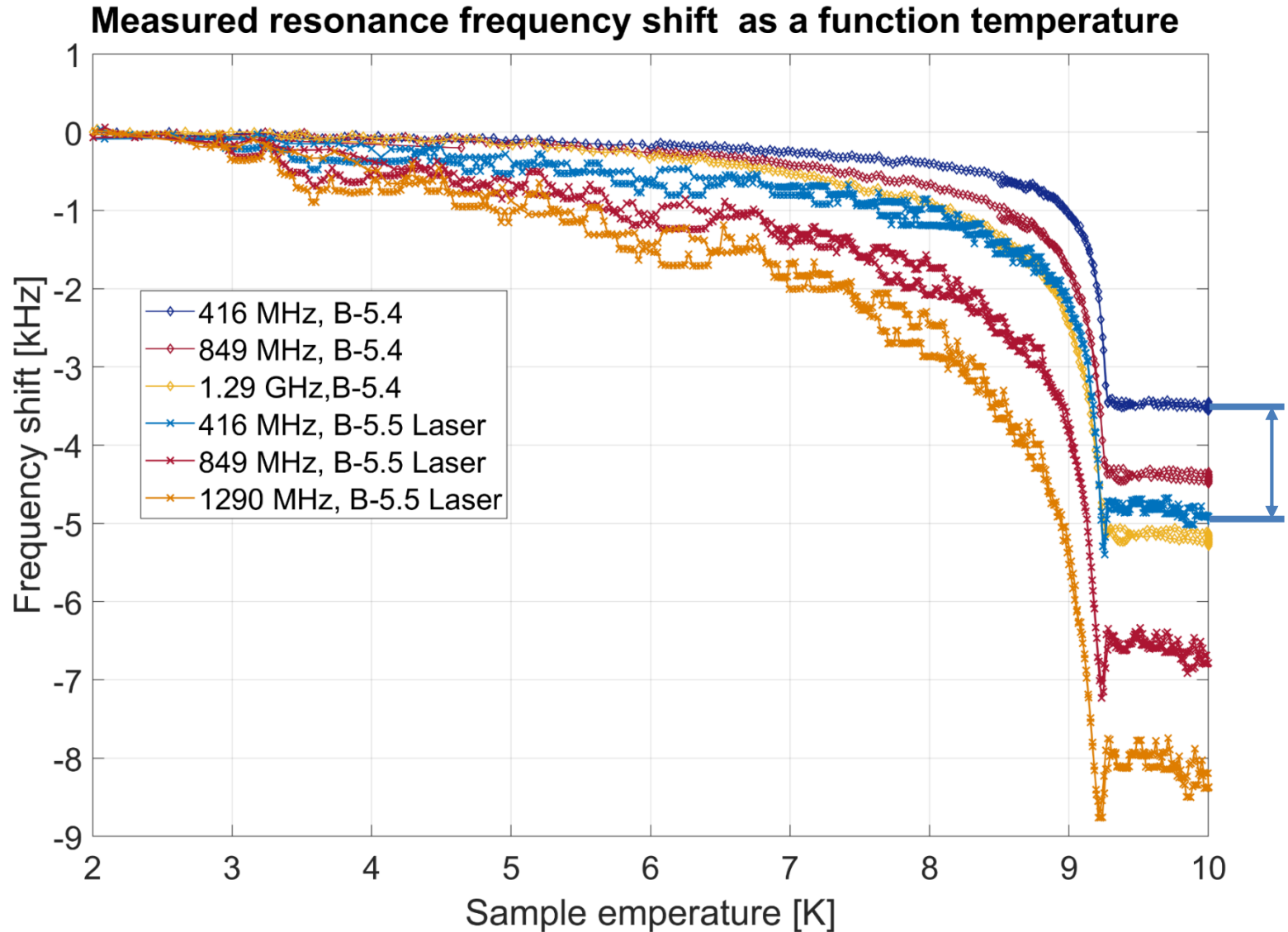
B-5
sample

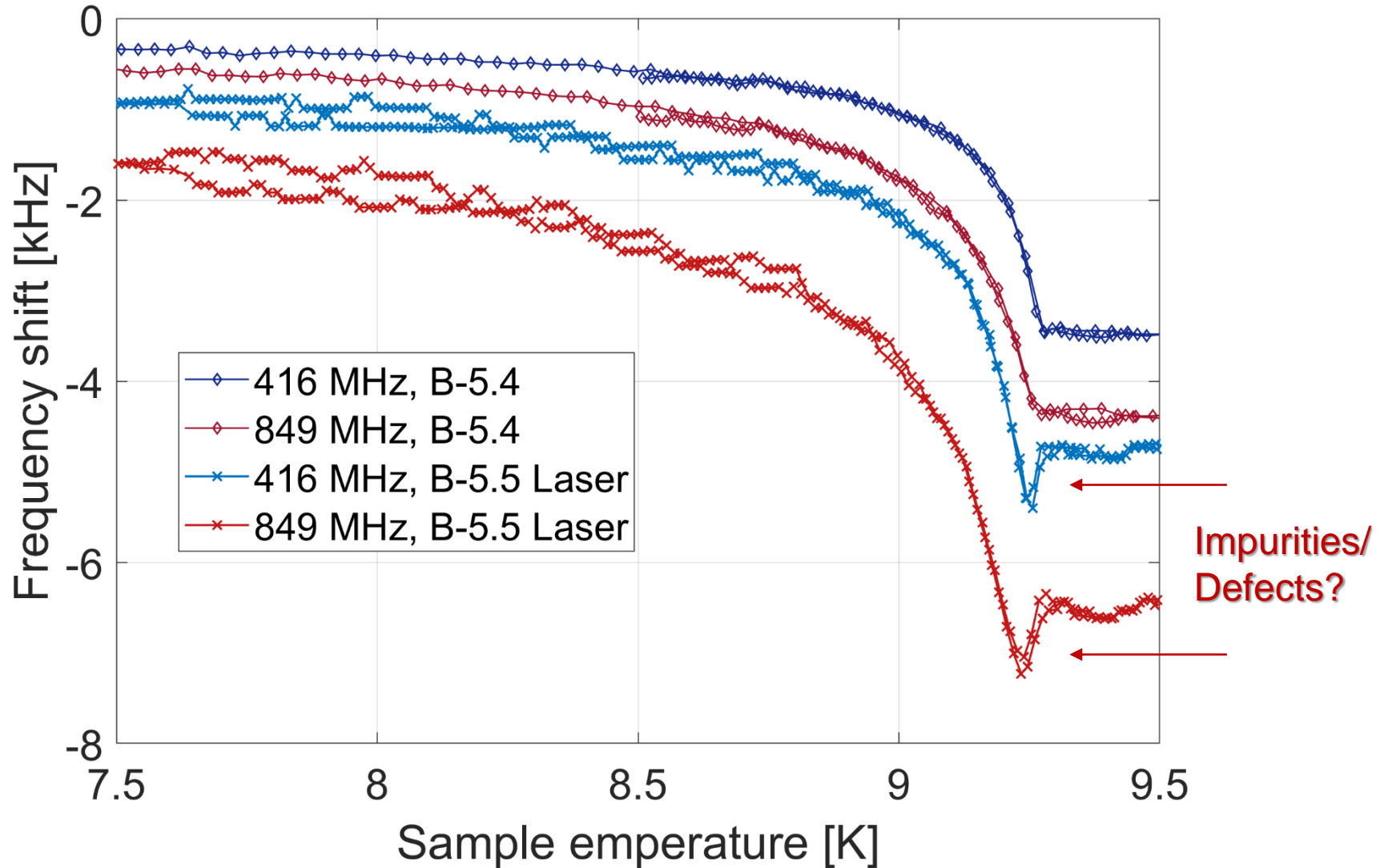


B-4
sample

Conclusions:

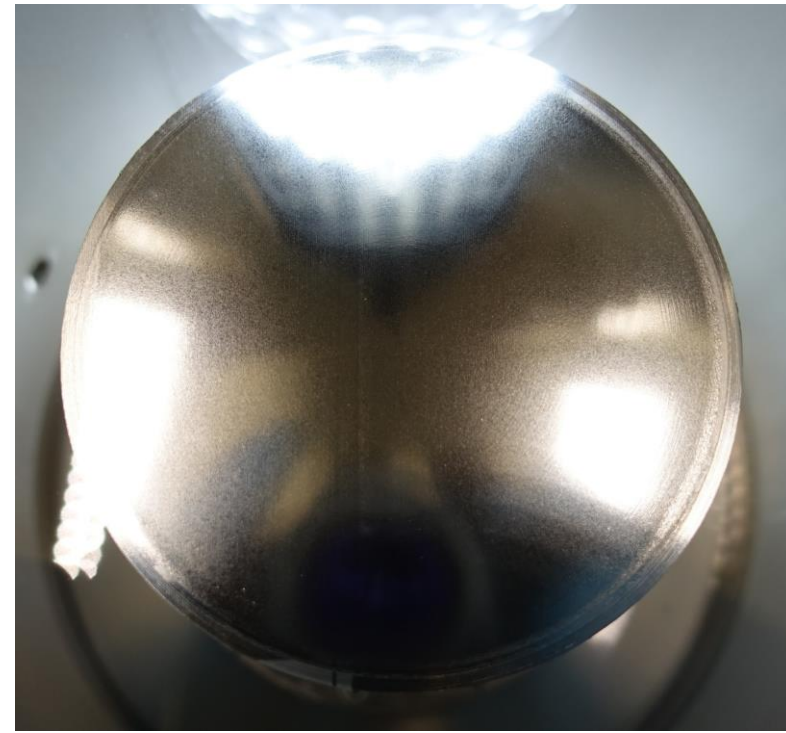
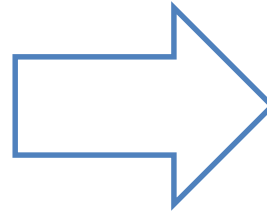
For the reliable data, next samples should be treated same way (flash etching, etc) to remove sharp pieces of Nb from edges







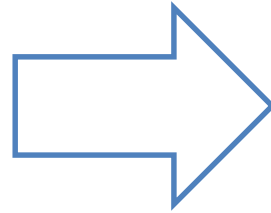
Pre LP:



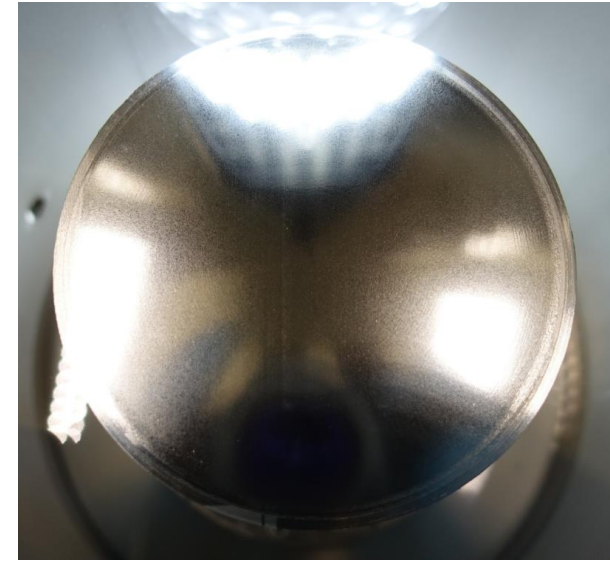
Post LP:



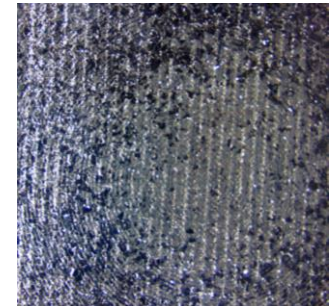
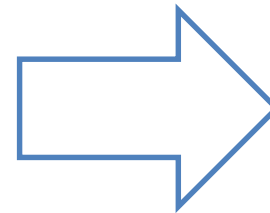
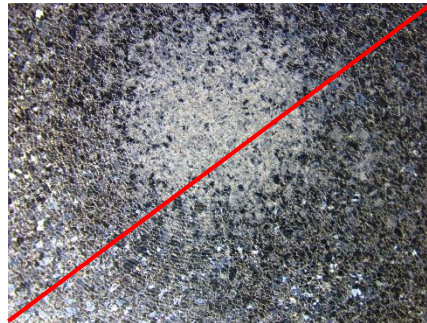
Pre LP:



- Some defects removed or partially removed

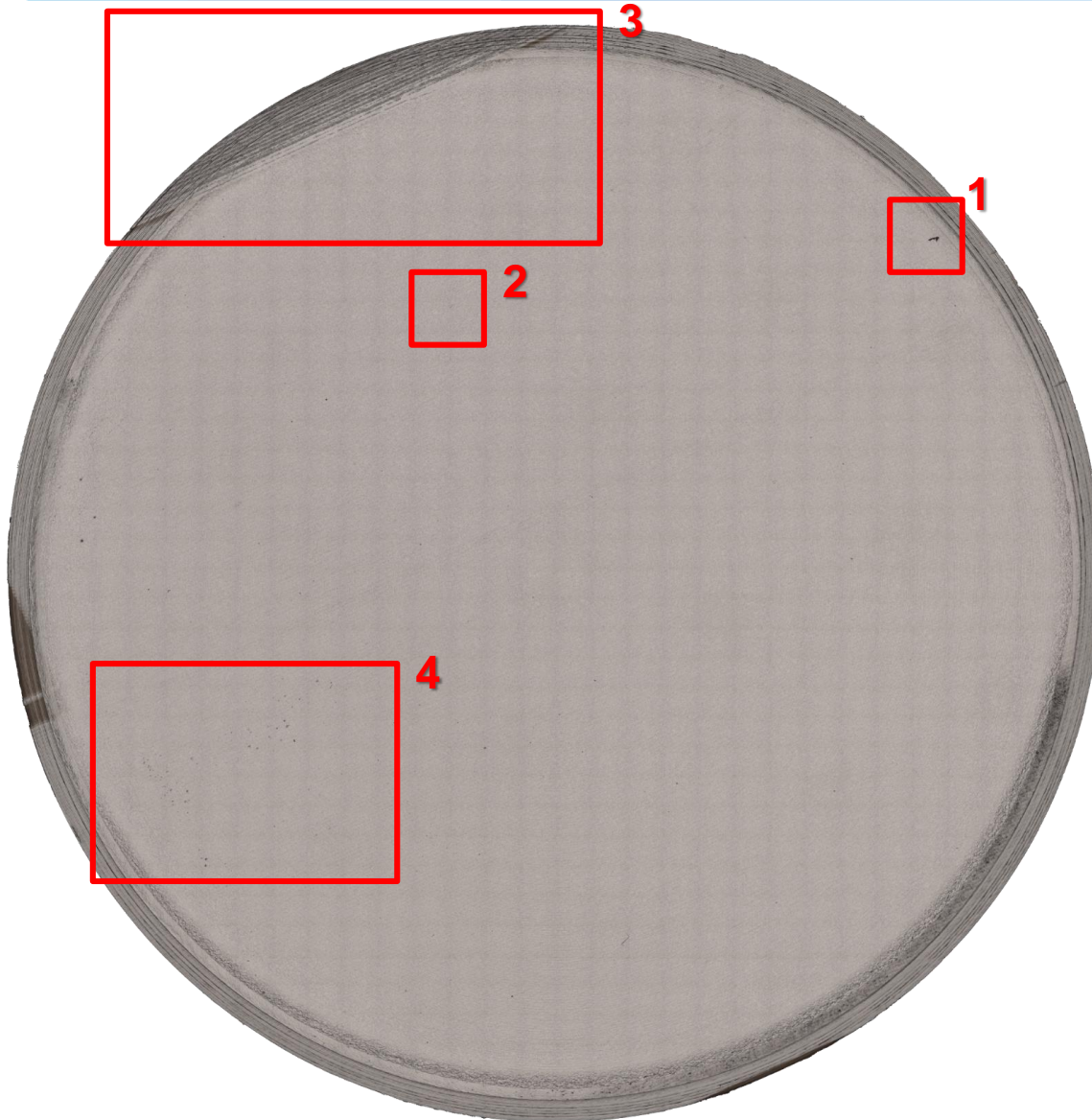


Post LP:





- Sample scanned with the laser microscope:
- Defects detection
- Roughness measurements
- *Full size JPEG picture (34 MB) and other data are on the CERNbox folder (note, that some features = dust)*



Some observed features:

1. Major defect near the edge
2. Minor craters in high field region
3. Laser traces (overpower?) near the edge
4. A “group of craters”



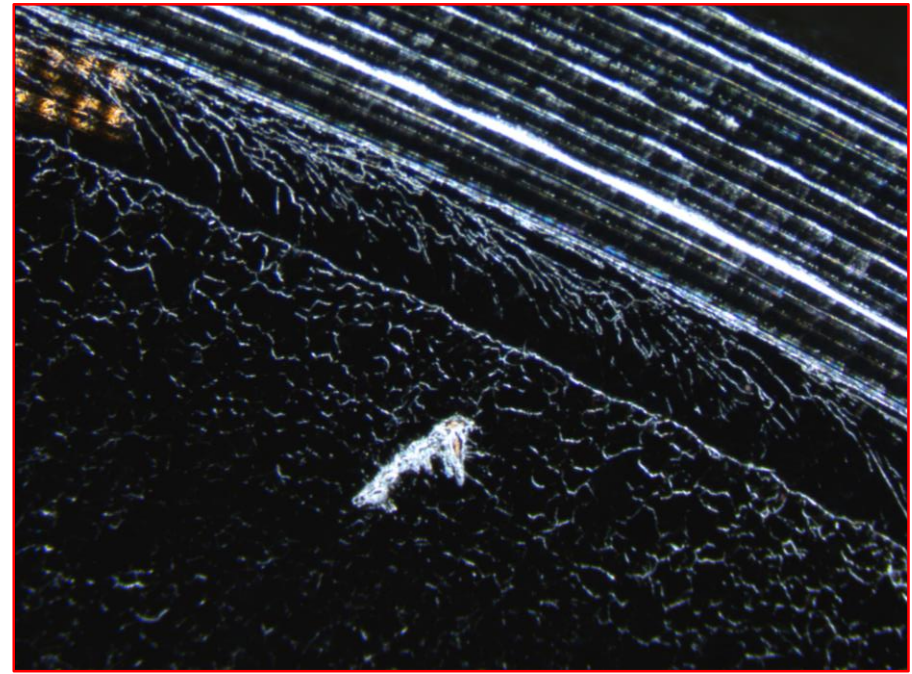
This pattern = effect of stitching

Defect 1 found near the edge:

Laser microscope view (5x):

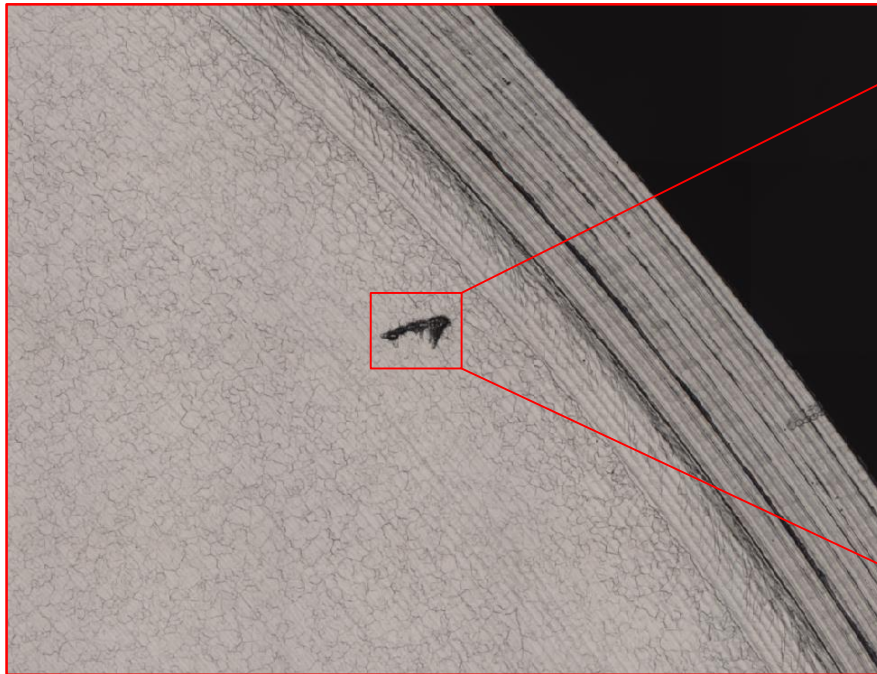


Optical microscope view:

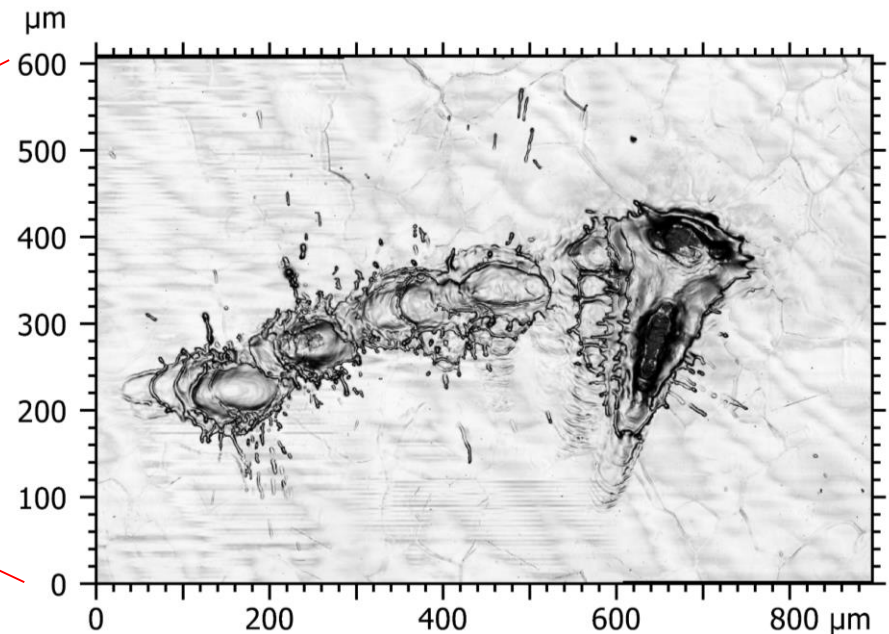


Defect 1 found near the edge:

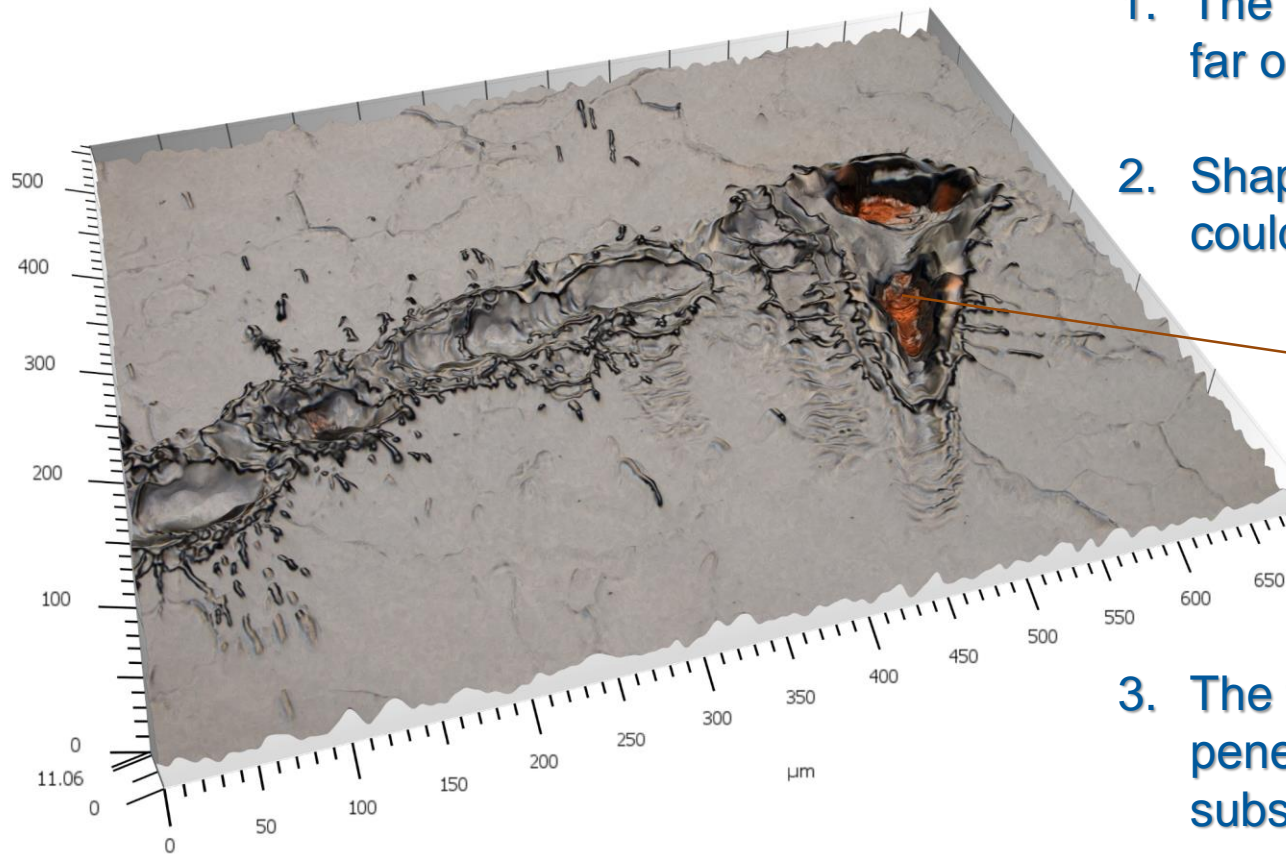
Laser microscope view (5x):



Laser microscope view (20x):



Defect 1 view from optics in 3D:

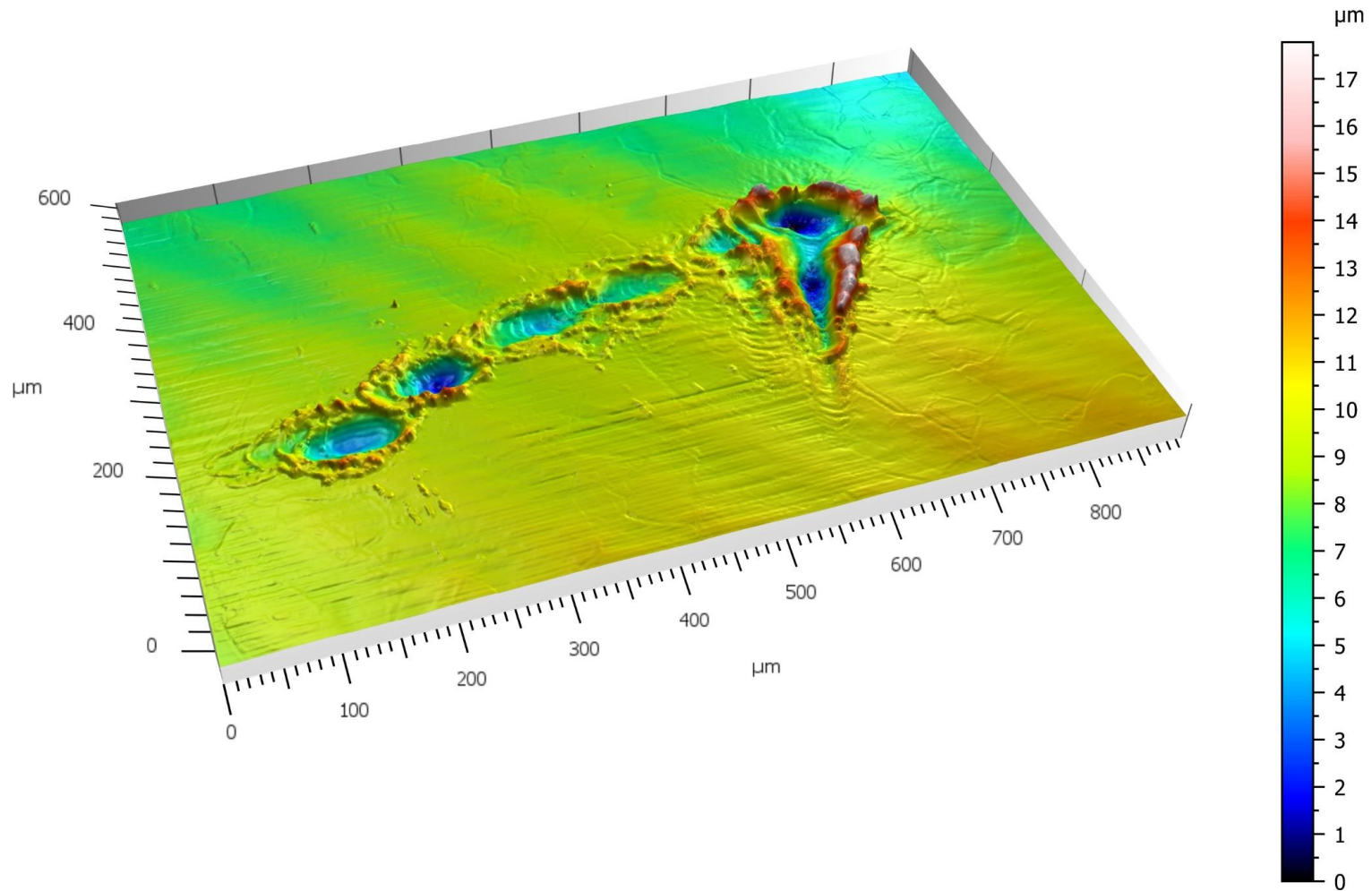


1. The defect was not found so far on pre-laser coated sample
2. Shape of the defect: the laser could give overpowered pulse

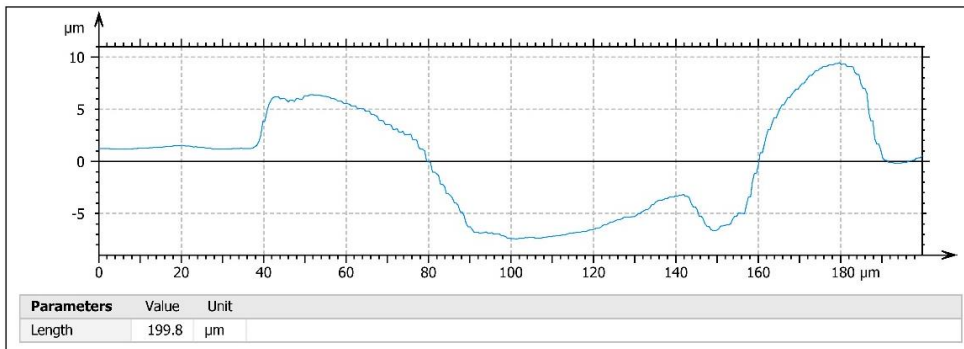
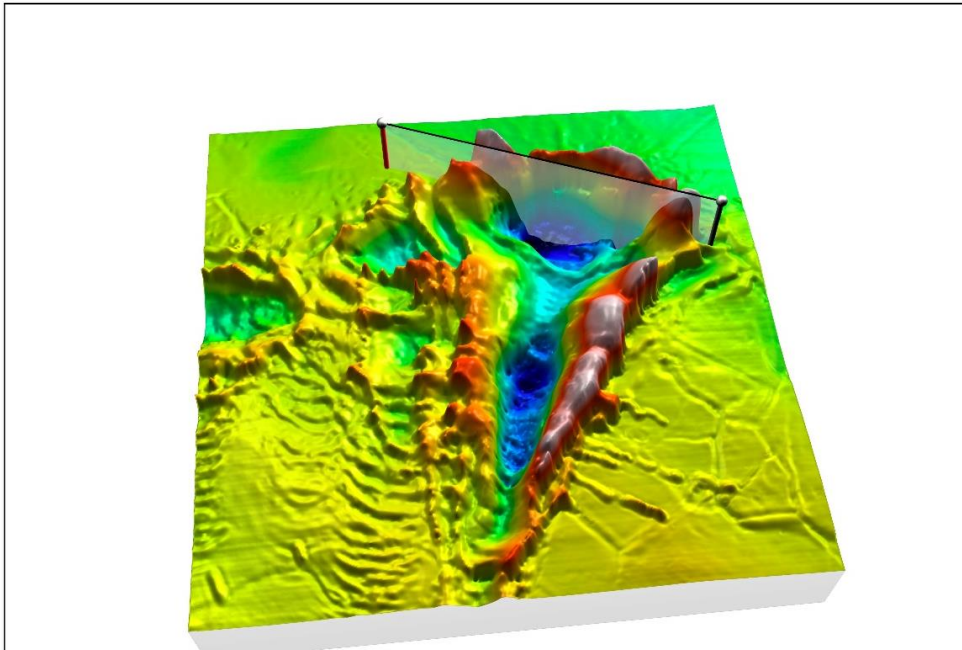
Cu?

3. The film is completely penetrated by the “shot”, substrate is exposed to RF

Defect 1 view in 3D:



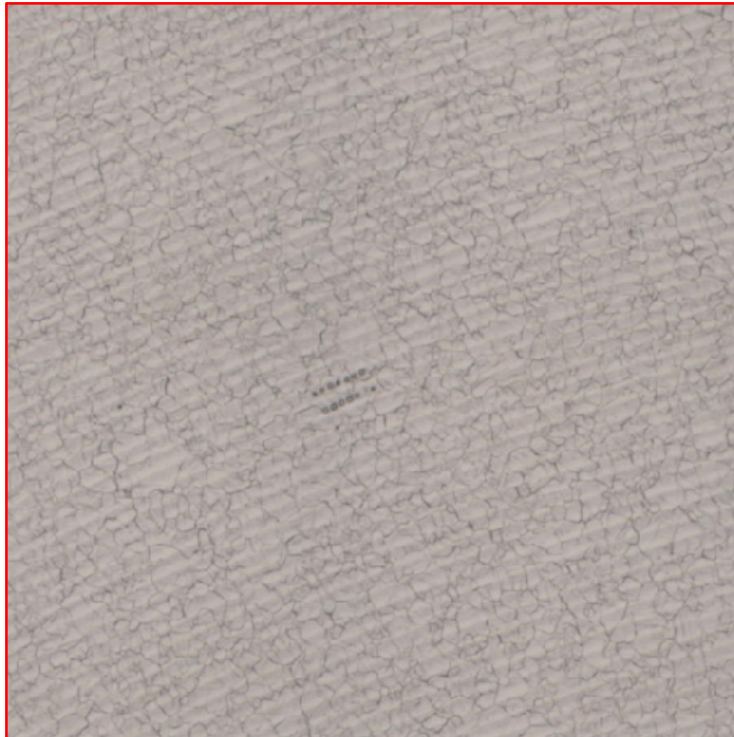
Defect 1 view in 3D:



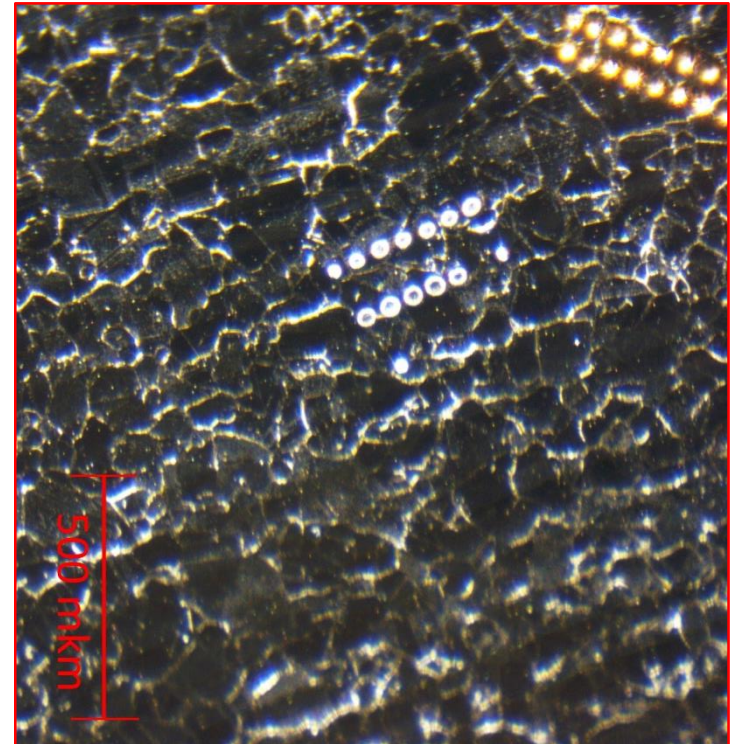
- The film deepness can be estimated about 5 mkm

Defect 2 found in the high RF field region:

Laser microscope view (5x):

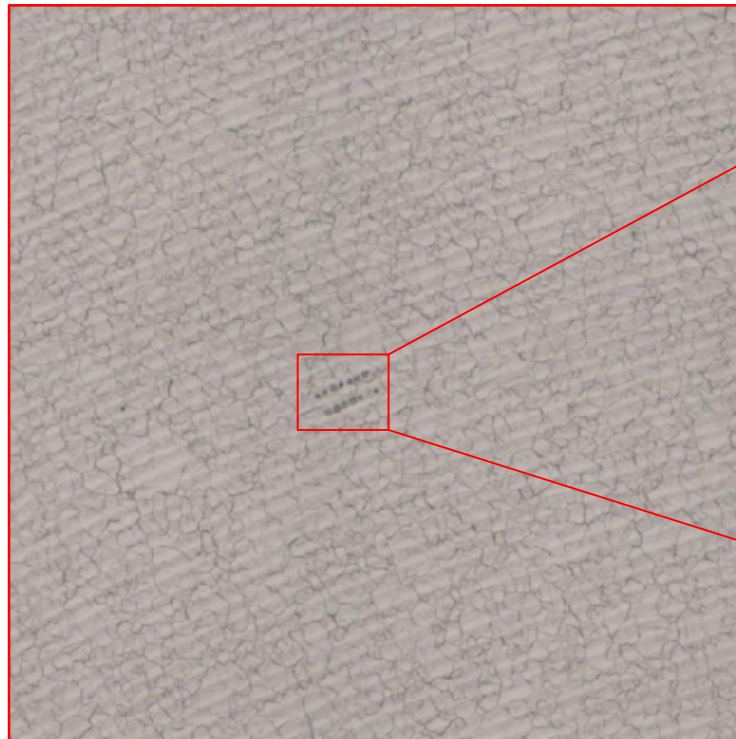


Optical microscope view:

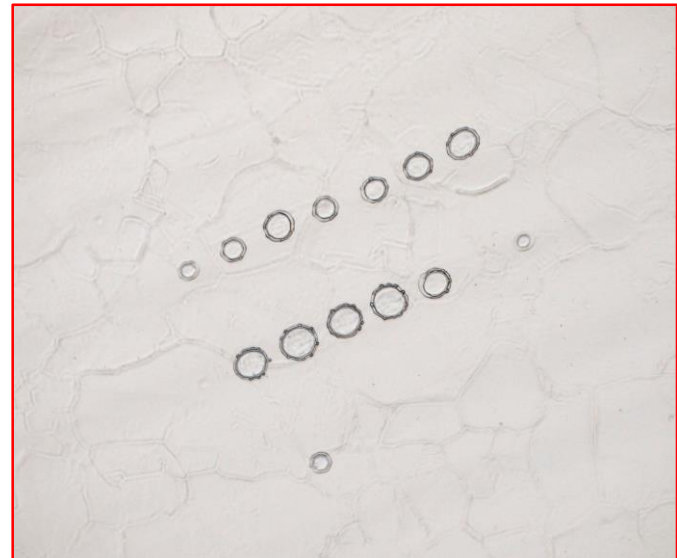


Defect 2 found in the high RF field region:

Laser microscope view (5x):



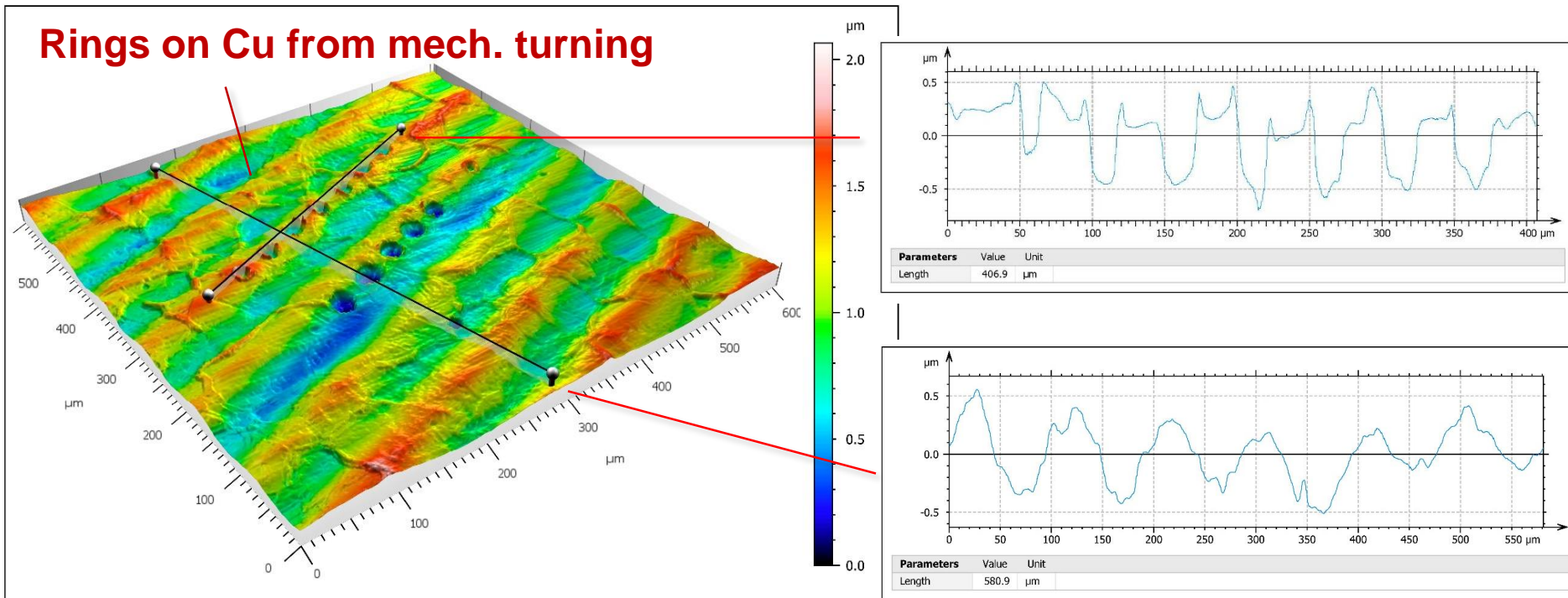
Laser microscope view (20x):



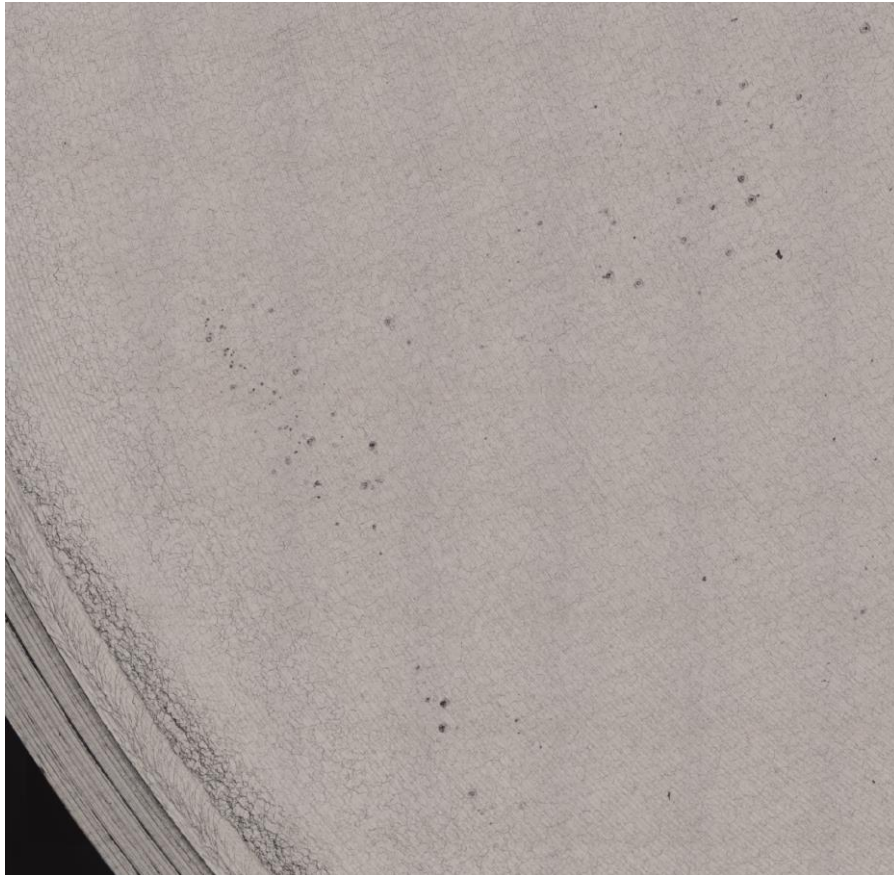
Defect 2 found in the high RF field region:

- Defect again looks like a crater (series of craters), deepness up to 1 mkm
- Roughness from substrate shape (due to mechanical production) is about 1 mkm

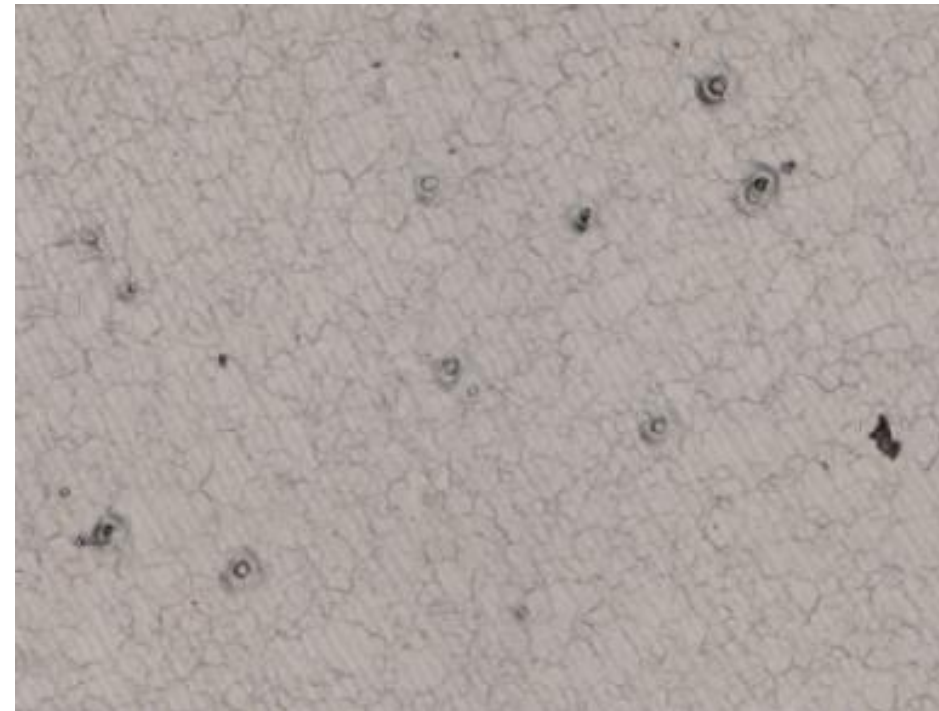
Rings on Cu from mech. turning



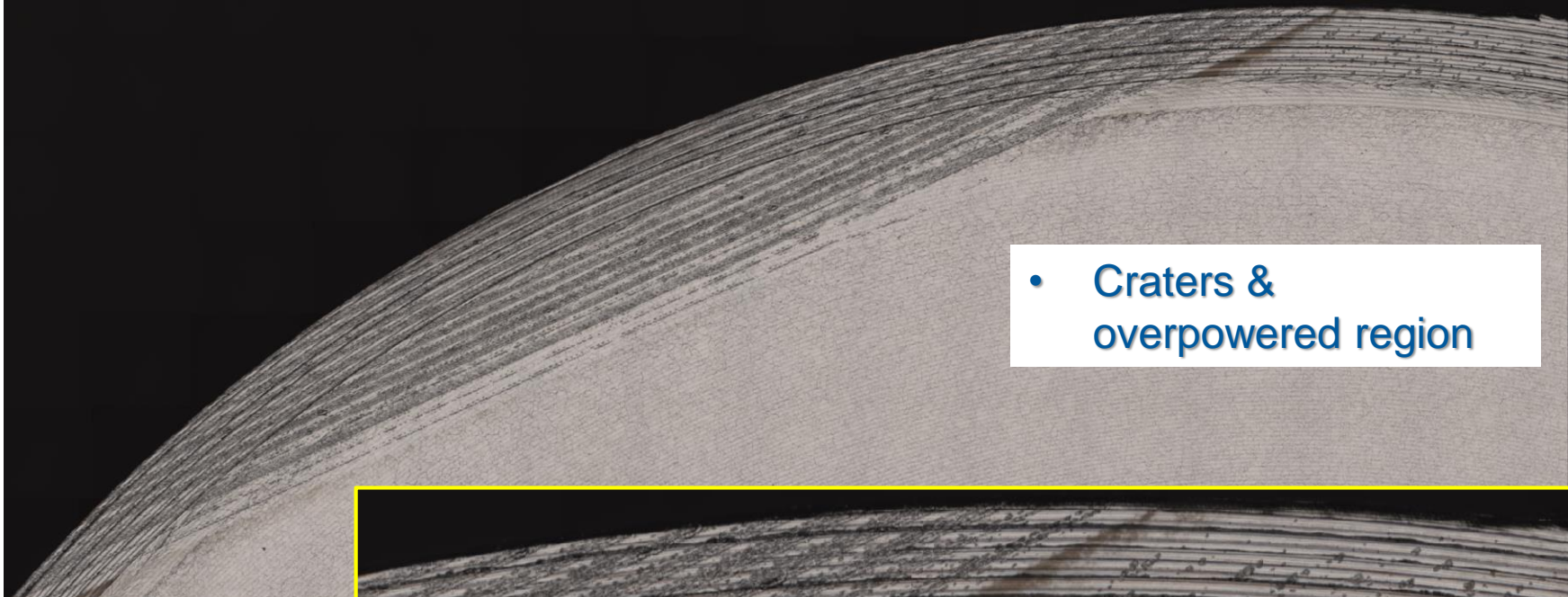
Laser microscope view (5x):



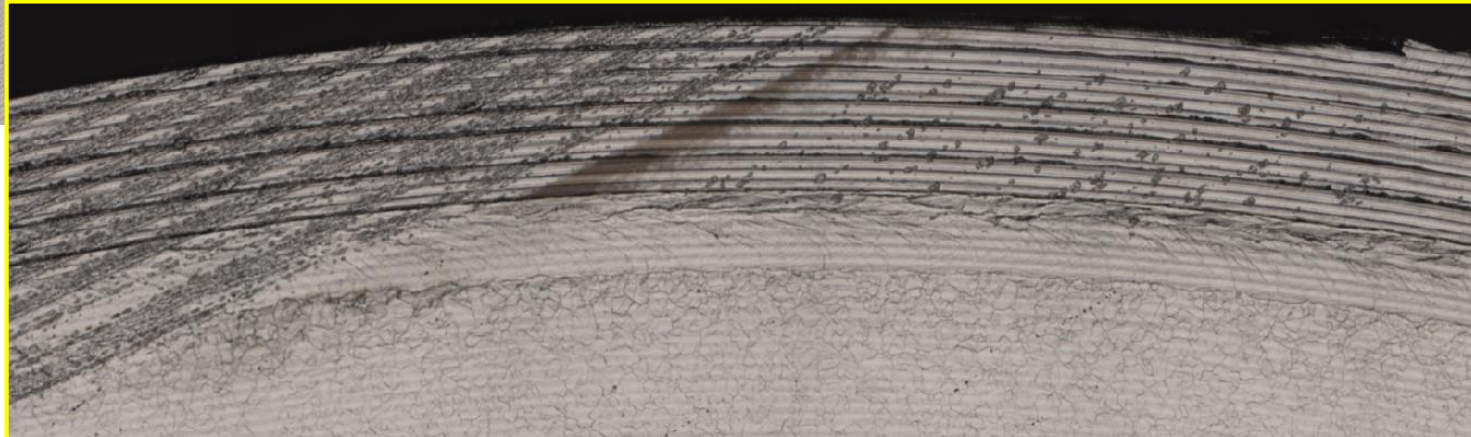
- Craters again?



Laser microscope view (5x):



- Craters & overpowered region



CONCLUSIONS

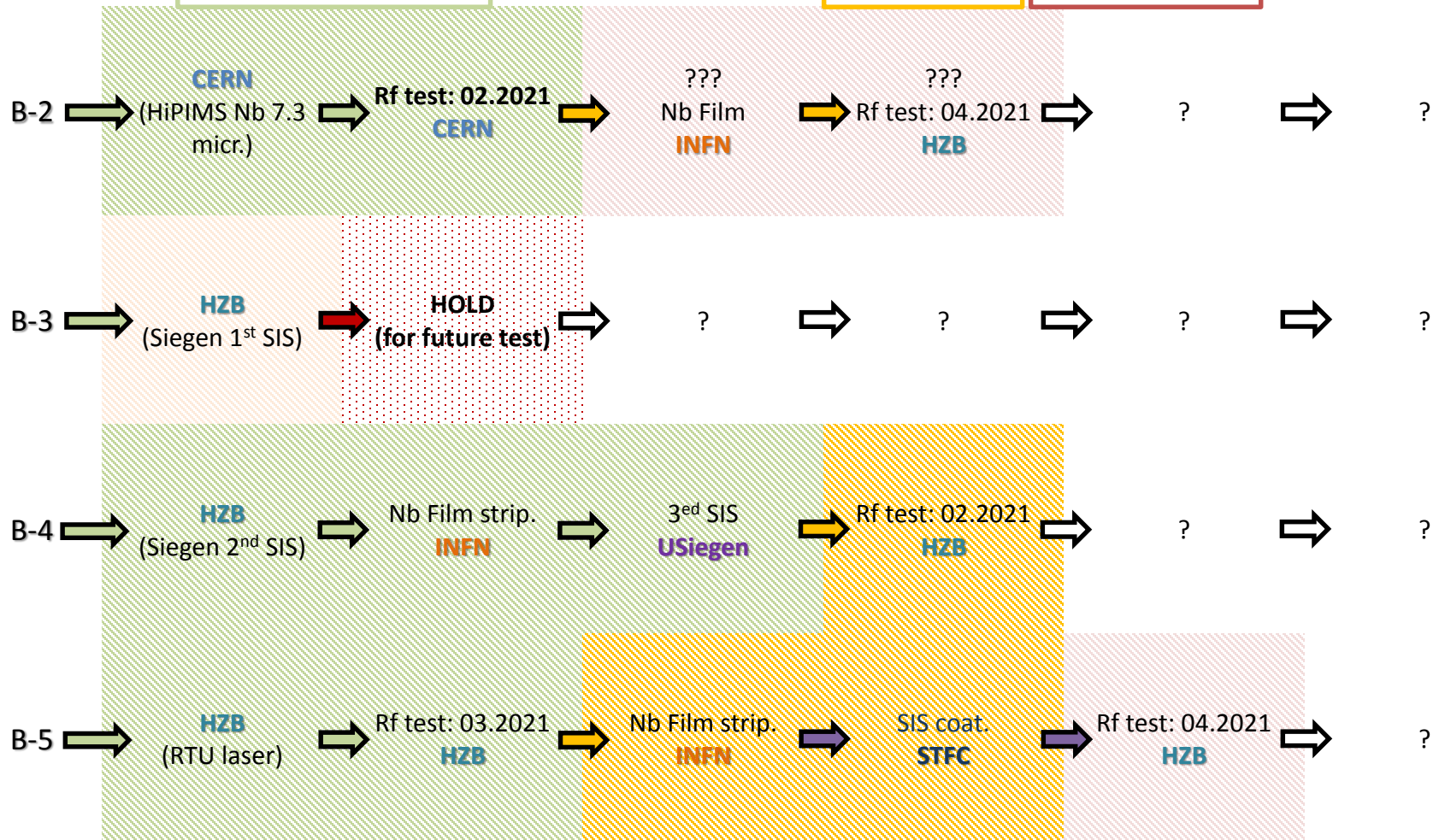
- Laser polishing practically can work
- Minor improvements at Rs vs B behavior. The problem with the rough edges is still present, and % of contribution of it to the final result is not clear.
- Film (probably) got some contaminations and defects during the process (conclusion from R_{BCS} and FvsT data).
- The process needs to be adjusted and surface analyzed more carefully.

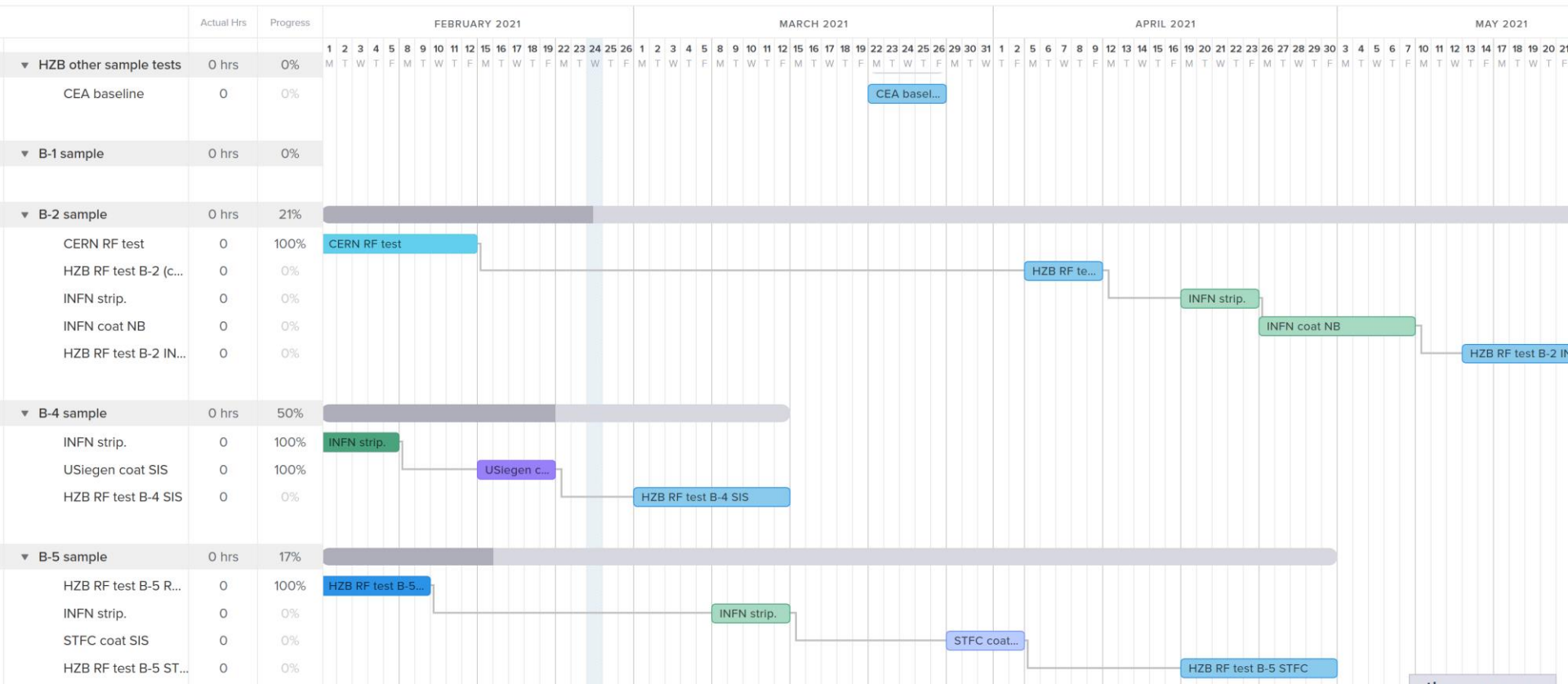


Now 25.01.2021

Next plan

Future plan





SUGGESTED NEXT STEPS

- If possible (not at HZB): Any analyses regarding molecular components of the film and/or SEM microscope scan
- Suggestions: Stripping of the top layer of the film and retesting to see if the contaminations are removed?

